International **IPR** Rectifier

HEXFET® TRANSISTOR

IRFV260

N-CHANNEL

200 Volt, 0.060Ω, HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits and virtually any application where high reliability is required.

The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

Product Summary

Part Number	BVDSS	RDS(on)	lD
IRFV260	200V	0.060Ω	45A*

Features:

- Hermetically Sealed
- Electrically Isolated
- Simple Drive Requirements
- Ease of Paralleling
- Ceramic Eyelets

	Parameter	IRFV260	Units				
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	45*					
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	29	A				
IDM	Pulsed Drain Current ①	180					
P _D @ T _C = 25°C	Max. Power Dissipation	300	W				
	Linear Derating Factor	2.4	W/K ©				
VGS	Gate-to-Source Voltage	Source Voltage ±20					
EAS	Single Pulse Avalanche Energy 2	700	mJ				
IAR	Avalanche Current ①	45	A				
EAR	Repetitive Avalanche Energy ①	30	mJ				
dv/dt	Peak Diode Recovery dv/dt ③	4.3	V/ns				
Тј	Operating Junction	-55 to 150					
TSTG	Storage Temperature Range		°C				
	Lead Temperature 300 (0.063	in. (1.6mm) from case for 10 sec.)					
	Weight	10.9 (typical)	g				

Absolute Maximum Ratings

* ID current limited by pin diameter

Parameter			Тур.	Max.	Units	Test Cor	ditions
BVDSS	Drain-to-Source Breakdown Voltage	200	—	—	V	VGS = 0V, I	D = 1.0 mA
ΔBV _{DSS} /ΔTJ	Temp. Coefficient of Breakdown Voltage	_	0.24	_	V/°C	Reference to 25°C, ID = 1.0 mA	
RDS(on)	Static Drain-to-Source		—	0.060		VGS = 10V, ID =29A ④	
	On-State Resistance	—	—	0.068	Ω	VGS = 10V	, I _D = 45A
VGS(th)	Gate Threshold Voltage	2.0	—	4.0	V	V _{DS} = V _{GS} ,	I _D = 250μA
9fs	Forward Transconductance	22	_	-	S (Ω)	$V_{DS} \ge 15V$, I	DS = 29A ④
IDSS	Zero Gate Voltage Drain Current	_	_	25	μA	V _{DS} =0.8 x Max	Rating,VGS=0V
		_	_	250	•	V _{DS} = 0.8 x	Max Rating
						VGS = 0V, 1	J = 125°C
IGSS	Gate-to-Source Leakage Forward	_	_	100	nA	V _{GS} =	= 20V
IGSS	Gate-to-Source Leakage Reverse	—	—	-100		VGS =	-20V
Qg	Total Gate Charge	—	—	230		VGS =10V,	I _D = 45A
Qgs	Gate-to-Source Charge	—	—	40	nC	V _{DS} = Max.	Rating x 0.5
Qgd	Gate-to-Drain ("Miller") Charge	—	—	110			
^t d(on)	Turn-On Delay Time	—	—	29		V _{DD} = 100\	/, I _D =45A,
tr	Rise Time	—	—	120	ns	RG = 2.35Ω,	VGS =10V
^t d(off)	Turn-Off Delay Time	—	—	110			
tf	FallTime	—	—	92			
LD	Internal Drain Inductance		8.7	_		Measured from the drain lead, 6mm (0.25 in.) from package to center of die.	Modified MOSFET symbol showing the internal inductances.
LS	Internal Source Inductance	_	8.7	_	nH	Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.	
C _{iss}	C _{iss} Input Capacitance		5100	—		VGS = 0V, \	/DS = 25V
C _{oss}	Output Capacitance		1100	—	рF	f = 1.0	MHz
C _{rss}	Reverse Transfer Capacitance	—	280	—			

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

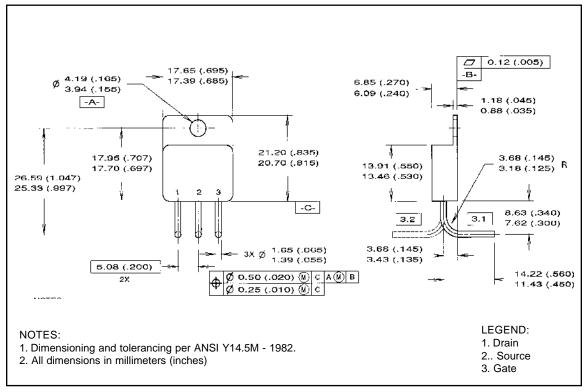
Parameter			Тур.	Max.	Units	Test Conditions
IS	Continuous Source Current (Body Diode)		-	45*		Modified MOSFET symbol showing the
ISM	SM Pulse Source Current (Body Diode) ①		—	180	А	integral reverse p-n junction rectifier.
VSD	D Diode Forward Voltage		—	1.8	V	$T_j = 25^{\circ}C, I_S = 45A, V_{GS} = 0V$ (4)
trr	Reverse Recovery Time		—	420	ns	Tj = 25°C, IF = 45A, di/dt \leq 100A/ μ s
QRR	Reverse Recovery Charge	—	—	4.9	μC	$V_{DD} \leq 50V$ (4)
ton	Forward Turn-On Time Intrinsic tur	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $L_S + L_D$.				

Source-Drain Diode Ratings and Characteristics

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
RthJC	Junction-to-Case	_	_	0.42		
R _{th} JA	Junction-to-Ambient	—	—	30	K/W (5)	typical socket mount
RthCS	Case-to-Sink	—	0.21	—		mounting surface flat, smooth

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② @ VDD = 50V, Starting TJ = 25°C, EAS = $[0.5 * L * (I_{L}^{2}) * [BVDSS/(BVDSS-VDD)]$ Peak IL = 45A, VGS = 10V, 25 \leq RG \leq 200 Ω
- Pulse width \leq 300 $\mu s;$ Duty Cycle \leq 2%
- ⑤ K/W = °C/W
 - $W/K = W/^{\circ}C$



Case Outline and Dimensions — TO-258AA

CAUTION BERYLLIA WARNING PER MIL-PRF-19500

Packages containing beryllia shall not be ground, sandblasted, machined, or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxides packages shall not be placed in acids that will produce fumes containing beryllium.

International

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331 EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020 IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897 IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590 IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111 IR FAR EAST: K&H Bldg., 2F, 3-30-4 Nishi-Ikeburo 3-Chome, Toshima-Ki, Tokyo Japan 171 Tel: 81 3 3983 0086 IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371 http://www.irf.com/ Data and specifications subject to change without notice. 7/96